Ň National Semiconductor

CGS701AV Commercial Low Skew PLL 1 to 8 CMOS Clock Driver CGS701ATV

Industrial Low Skew PLL 1 to 8 CMOS Clock Driver

CLK

GND

SEL

VCCA

GNDA

TI /F/11920-1

SEL

General Description

CGS701A is an off the shelf clock driver specifically designed for today's high speed designs. It provides low skew outputs which are produced at different frequencies from three fixed input references. The XTALIN input pin is designed to be driven from a 25 MHz-40 MHz crystal oscillator.

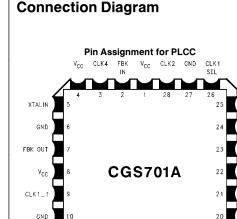
The PLL, using a charge pump and an internal loop filter, multiplies this input frequency to create a maximum output frequency of four times the input.

The device includes a TRI-STATE® control pin to disable the outputs. This feature allows for low frequency functional testing and debugging.

Also included, is an EXTSEL pin to allow testing the chip via an external source. The EXTSEL pin, once set to high, causes the External-Clock_MUX to change its input from the output of the VCO and Counter to the external clock signal provided via SKWTST input pin. (continued)

Features

- Guaranteed:
- 400 ps pin-to-pin skew (t_OSHL and t_OSLH) on 1X outputs.
- Pentium[®] and PowerPCTM compatible
- ±300 ps propagation delay
- Output buffer of eight drivers for large fanout
- 25 MHz-160 MHz output frequency range
- Outputs operating at 4X, 2X, 1X of the reference frequency for multifrequency bus applications
- Selectable output frequency
- Internal loop filter to reduce noise and jitter
- Separate analog and digital V_{CC} and ground pins
- Low frequency test mode by disabling the PLL
- Implemented on National's Core CMOS process
- Symmetric output current drive: +30/-30 mA I_{OL}/I_{OH}
- Industrial temperature of -40°C to +85°C
- 28-pin PLCC for optimum skew performance
- Guaranteed 2k volts ESD protection



CLK 1_3 GND CLK V_{CC} SK¥

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PowerPC™ is a trademark of International Business Machines Corporation

1_4

Pin Description

PLCC Package

Pin	Name	Description
1	V _{CC}	Digital V _{CC}
2	FBK IN	Feedback Input Pin
3	CLK4	4X Clock Output
4	V _{CC}	Digital V _{CC}
5	XTALIN	Crystal Oscillator Input
6	GND	Digital Ground
7	FBK OUT	Feedback Output Pin
8	V _{CC}	Digital V _{CC}
9	CLK1_I	1X Clock Output
10	GND	Digital Ground
11	CLK1_2	1X Clock Output
12	TRI-STATE	Output TRI-STATE Control
13	SKWTST	Skew Testing Pin
14	CLK1_3	1X Clock Output
15	GND	Digital Ground
16	CLK1_4	1X Clock Output
17	V _{CC}	Digital V _{CC}
18	SKWSEL	Skew Test Selector Pin
19	GNDA	Analog Ground
20	V _{CCA}	Analog V _{CC}
21	EXTSEL	External Clock MUX Selector
22	GND	Digital Ground
23	CLK1_5	1X Clock Output
24	V _{CC}	Digital V _{CC}
25	CLK1_0	1X Clock Output
26	CLK1SEL	CLK1 Multiplier Selector
27	GND	Digital Ground
28	CLK2	2X Clock Output

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STATE TST

CLK1 2

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ດດ GS701AV Commercial Low Skew Pl F to 8 ω **CMOS Clock Driver** CMOS **Clock Drive**

December 1995

CGS701A

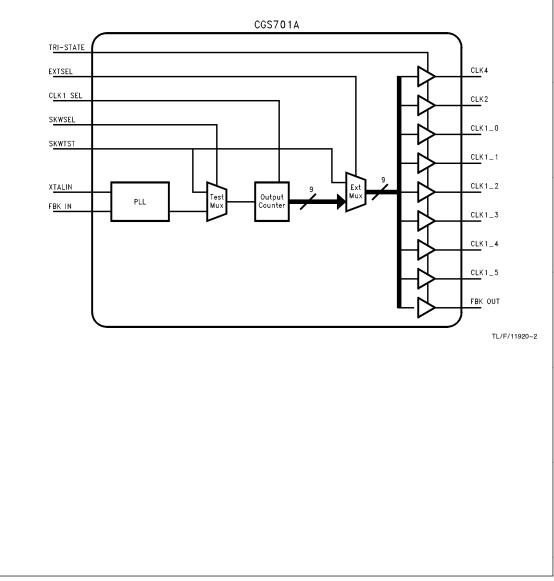
General Description (Continued)

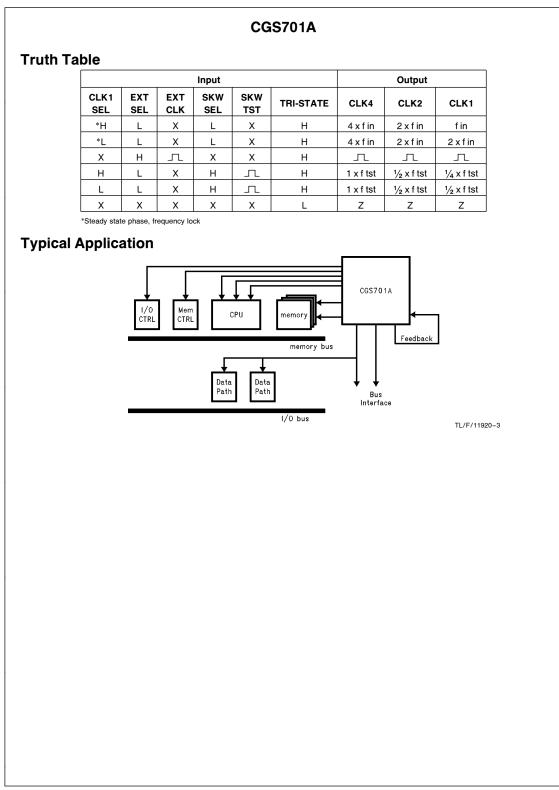
CLK1SEL pin changes the output frequency of the CLK1_0 thru CLK1_5 outputs. During normal operation, when CLK1SEL pin is high, these outputs are at the same frequency as the input crystal oscillator, while CLK2 and CLK4 outputs are at twice and four times the input frequency respectively.

Once CLK1SEL pin is set to a low logic level, the CLK1 outputs will be at twice the input frequency, the same as the CLK2 output, with CLK4 output still being at four times the input frequency.

Block Diagram

In addition, another pin is added for increasing the test capability. SKWSEL pin allows testing of the counter's output and skew of the output drivers by bypassing the VCO. In this test mode CLK4 frequency is the same as SKWTST input frequency, while CLK2 is 1/2 and CLK1 frequencies are 1/4 respectively (refer to the Truth Table). In addition CLK1SEL functionality is also true under this test condition.





CGS701A

Absolute Maximum Ratings (Note A)

If Military/Aerospace specified devices are required, ple Of Su

Recommended Operating Conditions

1 0 ()		Supply Voltage (V ₀ Input Voltage (V ₁) Output Voltage (V ₀ Input Frequency Operating Temper: External Clock Fre XTALIN Duty Cycle) ature (T _A) SKWTST quency (Pin)	25 MH 0°0 1 MH	4.5V to 5.5V 0V to V_{CC} 0V to V_{CC} Hz-40 MHz C to + 70°C Hz-10 MHz 5 (75/25)%
DC Output Diode Current (I _O) V = -0.5V $V = V_{CC} + 0.5V$ DC Output Voltage (V _O)	−20 mA + 20 mA −0.5V to V _{CC} + 0.5V		I Times (0.8V to 2.0		5 ns max 10 ns max
DC Output Source or Sink Current (I _O) DC V _{CC} or Ground Current per Output Pin (I _{CC} or I _{GND})	±60 mA	Typical $ heta_{JA}$	LFM 0 225 500	° C/W 54 45 38	
Storage Temperature (T _{STG}) Junction Temperature	-65°C to +150°C 150°C		900	34	
Power Dissipation (Static and Dynamic) (Note B)	1400 mW				

Note A: The Absolute Maximum Ratings are those values beyond which the safety of the device cannot be guaranteed. The device should not be operated at these limits. The parametric values defined in the DC and AC Electrical Characteristics tables are not guaranteed at the absolute maximum ratings. The Recommended Operating Conditions will define the conditions for actual device operation.

Note B: Power dissipation is calculated using 49°C/W as the thermal coefficient for the PCC package at 225 LFM airflow. The input frequency is assumed at 33 MHz with CLK4 at 132 MHz and CLK2 and CLK1 being at 66 MHz. In addition, the ambient temperature is assumed 70°C.

DC Electrical Characteristics

Over recommended operating free air temperature range. All typical values are measured at V_{CC} = 5V, T_A = 25°C.

Symbol	Parameter		CC = 4.5V-5.5 = 0°C to 70°	Units	Conditions		
		Min	Тур	Max			
V _{IH}	Minimum Input High Level Voltage	2.0			v		
V _{IL}	Maximum Input Low Level Voltage			0.8	v		
V _{OH}	Minimum Output High Level	$V_{CC} - 0.1$			- v	$I_{OUT} = -50 \ \mu A$	
	Voltage	$V_{CC} - 0.6$			v	$I_{OH} = -30 \text{ mA}$	
V _{OL}	Maximum Output Low Level			0.1	- v	$I_{OUT} = 50 \ \mu A$	
	Voltage			0.6	v	$I_{OL} = 30 \text{ mA}$	
IOHD	High Level Output Current	-50	-110	-170	mA	$V_{\text{OH}} = V_{\text{CC}} - 1.0V$	
I _{OLD}	Low Level Output Current	50	110	170	mA	$V_{OL} = 1.0V$	
I _{IN}	Leakage Current	-50		50	μA	$V_{IN} = 0.4V \text{ or } 4.6V$	
I _{OZL/H}	Output Leakage Current						
C _{IN}	Input Capacitance			10.0	pF		
ICC	Quiescent digital + analog Current (No Load)		3.0	5.0	mA	$V_{IN} = V_{CC}$, GND	
ICCT	I _{CC} per TTL Input			2.5		$V_{IN} = V_{CC} - 2.1, GNE$	

			cteristics	CGS70 e range. All typica		e measur	ed at V _{CC}	= 5V, T ₄	4 = 25°C.
Symbol	Parameter			$\begin{split} V_{CC} &= 4.5V-5.5V\\ F_{IN} &= 25 \text{ to } 40 \text{ MHz}\\ T &= 0^\circ\text{C} \text{ to } + 70^\circ\text{C}\\ C_L &= \text{Circuit 1}\\ R_L &= \text{Circuit 1} \end{split}$			Units	Notes	
					Min	Тур	Max		
t _{rise}	Output Rise	CLK4 CLK2 CLK1	0.8V to 2.6V 1.0V to V _{CC} $-$ 1 1.0V to V _{CC} $-$ 1				2.0	ns	(Note 1, 7)
		All	0.8V to 2.0V				1.5		
t _{fall}	Output Fall	CLK4 CLK2 CLK1	2.6V to 0.8V V _{CC} $-$ 1.0V to 1 V _{CC} $-$ 1.0V to 1				2.0	ns	(Note 1, 7)
		All	0.8V to 2.0V				1.5		
tSKEW	Maximum Ed Edge Output	0	+ to + Edges + to + Edges + to + Edges	CLK1_CLK1 CLK1_CLK4 CLK2_CLK4			400 1000 1000	ps	(Note 2, 7)
t _{LOCK}	Time to Lock	the Outp	ut to the Synch Inp	out		20	100	μs	
t _{CYCLE}	Output Duty (Cycle		CLK1 Outputs CLK2 Output CLK4 Output	49 49 35		51 51 65	%	(Note 3, 7)
J _{LT}	Output Jitter	(Long Tei	rm)				0.3	ns	(Note 4, 7)
t _{PD}	Propogation I	Delay from	m XTALIN to FBK	DUT	-0.3		+0.3	ns	(Notes 2, 4, 5, 6, 7)
F _{MIN}	Minimum XTA	LIN Free	luency				15	MHz	
F _{MAX}	Maximum XT	ALIN Fre	quency				43	MHz	

Note 1: t_{rise} and t_{fall} parameters are measured at the pin of the device.

Note 2: Skew is measured at 50% of V_{CC} for CLK1 and CLK2 while it is being measured at 1.4V for CLK4. Limits are guaranteed by design.

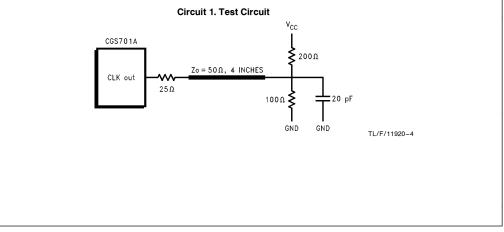
Note 3: Output duty cycle is measured at V_{DD}/2 for CLK1 and CLK2 while it is being measured at 1.4V for CLK4. Limits are guaranteed by design.

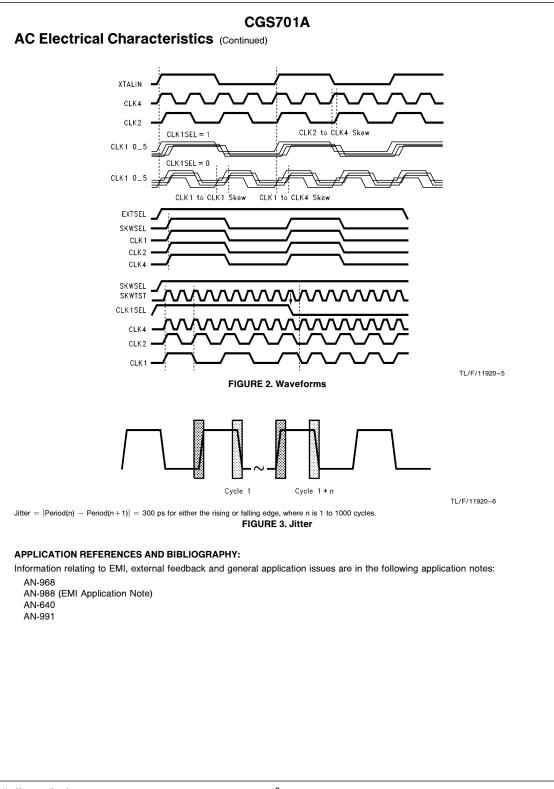
Note 4: Jitter parameter is characterized and is guaranteed by design only. It measures the uncertainty of either the positive or the negative edge over 1000 cycles. It is also measured at output levels of V_{CC}/2. Refer to *Figure 3* for further explanation.

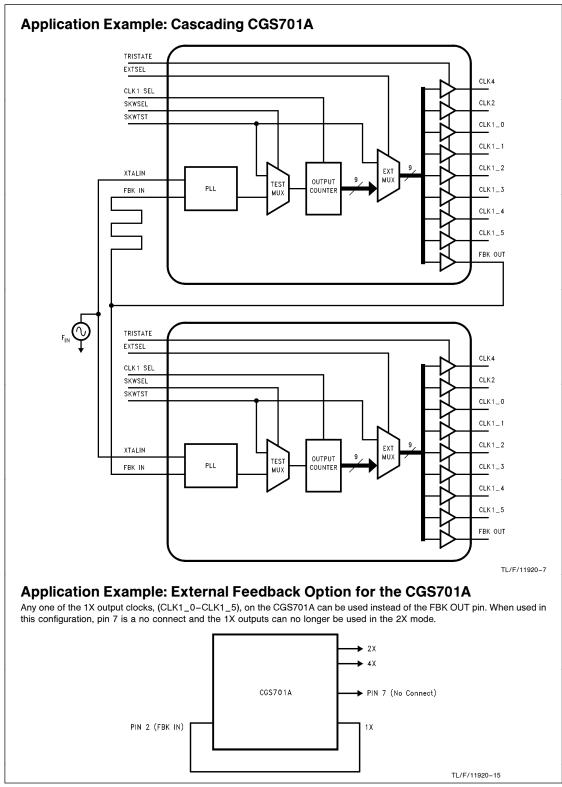
Note 5: Measured from the ref. input to any output pin. The length of the feedback and XTALIN traces will impact this delay time.

Note 6: This parameter includes pin-to-pin skew, longterm jitter over 1000 cycles, part-to-part variation as well as propagation delay thru the device.

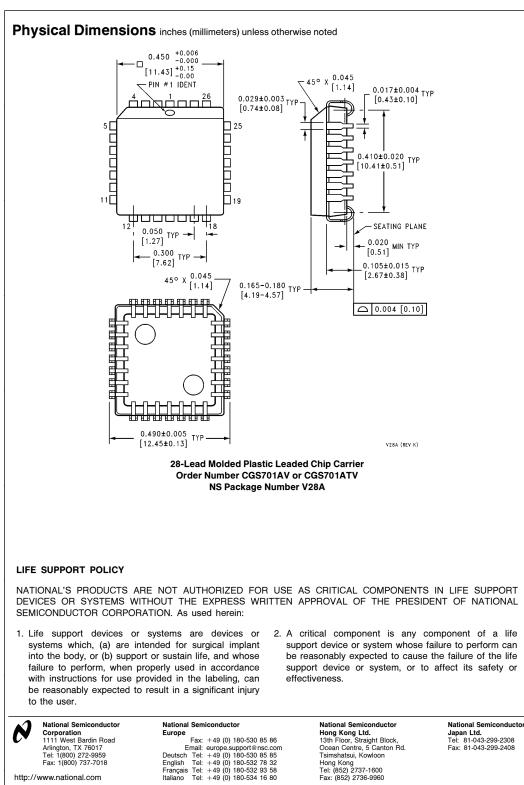
Note 7: The GNDA pins of the 701 must be as free of noise as possible for minimum jitter. Separate analog ground plane is recommended for the PCB. Also the V_{CCA} pin requires extra filtering to further reduce noise. Ferrite beads for filtering and bypass capacitors are suggested for the V_{CCA} pin.







Device Type		0	Tempera = Indust = Comme	rial	TL∕F∕1



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